



# IEEE Standard for Extensions to Standard Test Interface Language (STIL) (IEEE Std 1450<sup>TM</sup>-1999) for Tester Target Specification

---

**IEEE Computer Society**

Sponsored by the  
Test Technology Standards Committee

---

IEEE  
3 Park Avenue  
New York, NY 10016-5997, USA

7 September 2007

**IEEE Std 1450.3<sup>TM</sup>-2007**

Currently in preview, click buy full version

Recognized as an  
American National Standard (ANSI)

IEEE 1450.3™-2007

# IEEE Standard for Extensions to Standard Test Interface Language (STIL) (IEEE Std 1450™-1999) for Tester Target Specification

Sponsor

**Test Technology Standards Committee  
of the  
IEEE Computer Society**

Approved 24 August 2007

**American National Standards Institute**

Approved 8 March 2007

**IEEE SA-Standards Board**

**Abstract:** The STIL environment supports transferring tester-independent test programs to a specific automated testing equipment (ATE) system. Although native STIL data are tester independent, the actual process of mapping the test program onto tester resources may be critical, and it is necessary to be able to completely and unambiguously specify how the STIL programs and patterns are mapped onto the tester resources. TRC (which stands for either tester resource constraints or tester rules checking, depending on the usage) is an extension to the STIL language to facilitate this operation.

**Keywords:** Tester rules checking (TRC), tester resource reporting, tester resource targeting, tester resource loading

---

The Institute of Electrical and Electronics Engineers, Inc.  
3 Park Avenue, New York, NY 10016-5997, USA

Copyright © 2007 by the Institute of Electrical and Electronics Engineers, Inc.  
All rights reserved. Published 7 September 2007. Printed in the United States of America.

IEEE is a registered trademark in the U.S. Patent & Trademark Office, owned by the Institute of Electrical and Electronics Engineers, Incorporated.

Print: ISBN 0-7381-5517-9 SH95624  
PDF: ISBN 0-7381-5518-7 SS95624

*No part of this publication may be reproduced in any form, in an electronic retrieval system or otherwise, without the prior written permission of the publisher.*

**IEEE Standards** documents are developed within the IEEE Societies and the Standards Coordinating Committees of the IEEE Standards Association (IEEE-SA) Standards Board. The IEEE develops its standards through a consensus development process, approved by the American National Standards Institute, which brings together volunteers representing varied viewpoints and interests to achieve the final product. Volunteers are not necessarily members of the Institute and serve without compensation. While the IEEE administers the process and establishes rules to promote fairness in the consensus development process, the IEEE does not independently evaluate, test, or verify the accuracy of any of the information contained in its standards.

Use of an IEEE Standard is wholly voluntary. The IEEE disclaims liability for any personal injury, property or other damage, of any nature whatsoever, whether special, indirect, consequential, or compensatory, directly or indirectly resulting from the publication, use of, or reliance upon this, or any other IEEE Standard document.

The IEEE does not warrant or represent the accuracy or content of the material contained herein, and expressly disclaims any express or implied warranty, including any implied warranty of merchantability or fitness for specific purpose, or that the use of the material contained herein is free from patent infringement. IEEE Standards documents are supplied "**AS IS.**"

The existence of an IEEE Standard does not imply that there are no other ways to produce, test, measure, purchase, market, or provide other goods and services related to the scope of the IEEE Standard. Furthermore, the viewpoint expressed at the time a standard is approved and issued is subject to change brought about through developments in the state of the art and comments received from users of the standard. Every IEEE Standard is subjected to review at least every five years for revision or reaffirmation. When a document is more than five years old and has not been reaffirmed, it is reasonable to conclude that its contents, although still of some value, do not wholly reflect the present state of the art. Users are cautioned to check to determine that they have the latest edition of any IEEE Standard.

In publishing and making this document available, the IEEE is not suggesting or rendering professional or other services for, or on behalf of, any person or entity. Nor is the IEEE undertaking to perform any duty owed by any other person or entity to another. Any person utilizing this, and any other IEEE Standards document, should rely upon the advice of a competent professional in determining the exercise of reasonable care in any given circumstances.

**Interpretations:** Occasionally questions may arise regarding the meaning of portions of standards as they relate to specific applications. When the need for interpretations is brought to the attention of IEEE, the Institute will initiate action to prepare appropriate responses. Since IEEE Standards represent a consensus of concerned interests, it is important to ensure that any interpretation has also received the concurrence of a balance of interests. For this reason, IEEE and the members of its societies and Standards Coordinating Committees are not able to provide an instant response to interpretation requests except in those cases where the matter has previously received formal consideration. At lectures, symposia, seminars, or educational courses, an individual presenting information on IEEE standards shall make it clear that his or her views should be considered the personal views of that individual rather than the formal position, explanation, or interpretation of the IEEE.

Comments for revision of IEEE Standards are welcome from any interested party, regardless of membership affiliation with IEEE. Suggestions for changes in documents should be in the form of a proposed change of text, together with appropriate supporting comments. Comments on standards and requests for interpretations should be addressed to:

Secretary, IEEE-SA Standards Board  
445 Hoes Lane  
Piscataway, NJ 08854  
USA

Authorization to photocopy portions of any individual standard for internal or personal use is granted by the Institute of Electrical and Electronics Engineers, Inc., provided that the appropriate fee is paid to Copyright Clearance Center. To arrange for payment of licensing fee, please contact Copyright Clearance Center, Customer Service, 222 Rosewood Drive, Danvers, MA 01923 USA; +1 978 750 8400. Permission to photocopy portions of any individual standard for educational classroom use can also be obtained through the Copyright Clearance Center.

## Introduction

This introduction is not part of IEEE 1450.3-2007, Standard for Extensions to Standard Test Interface Language (STIL) (IEEE Std 1450™-1999) for Tester Target Specification.

STIL is a collection of standards with the base standard being 1450 and the dotted extensions used to define additional syntax for addressing additional areas; i.e., this standard addresses tester rules.

The extensions follow the same conventions as the base standard. The base and the extensions are developed so as to work together; i.e., STIL is a single language that is defined (and has been developed) as separate IEEE standards.

## Notice to users

### Errata

Errata, if any, for this and all other standards can be accessed at the following URL: <http://standards.ieee.org/reading/ieee/updates/errata/index.html>. Users are encouraged to check this URL for errata periodically.

### Interpretations

Current interpretations can be accessed at the following URL: <http://standards.ieee.org/reading/ieee/interp/index.html>.

### Patents

Attention is called to the possibility that implementation of this standard may require use of subject matter covered by patent rights. By publication of this standard, no position is taken with respect to the existence or validity of any patent rights in connection therewith. The IEEE shall not be responsible for identifying patents or patent applications for which a license may be required to implement an IEEE standard or for conducting inquiries into the legal validity or scope of those patents that are brought to its attention.

### Participants

The following is a list of participants in the STIL Working Group.

#### **Tony Taylor, *Chair***

John V. Cosley  
David Dowding  
Oleg Erlich  
Yung D. Fan  
Dave Gallagher

Bruce Kaufman  
Ken Mandl  
Gregory Maston  
Gary Murray  
Chris J. Nelson

Ken Posse  
Paul J. Reuter  
Jose M. Santiago  
Doug Sprague  
Allen Yeats

The following members of the individual balloting committee voted on this standard. Balloters may have voted for approval, disapproval, or abstention.

Keith Chow  
Tommy P. Cooper  
John V. Cosley  
Sourav K. Dutta  
Yung D. Fan  
Randall C. Groves  
Kazumi Hatayama  
Werner Hoelzl  
Chi Tin Hon  
Dennis Horwitz  
Hirofumi Kamitokusari  
Mark J. Knight

Susan K. Land  
Adam W. Ley  
G. L. Luri  
Gregory Maston  
Tom Micek  
Gary L. Michel  
Yinghua Min  
Chris J. Nelson  
Michael S. Newman  
Noriaki Okumiya  
Ulrich Pohl

Paul J. Reuter  
Robert A. Robinson  
Jose M. Santiago  
Bartien Sayogo  
Roger J. Sowada  
Walter Struppler  
K. S. Subrahmanyam  
Tony Taylor  
Srinivasa R. Vemuru  
Thomas M. Wandeloski  
Gregg Wilder  
Oren Yuen

When the IEEE-SA Standards Board approved this standard on 8 March 2007, it had the following membership:

**Steve M. Mills, *Chair***  
**Robert M. Grow, *Vice Chair***  
**Don Wright, *Past Chair***  
**Judith Gorman, *Secretary***

Alex Gelman  
William R. Goldbach  
Arnold M. Greenspan  
Joanna N. Guenin  
Julian Forster\*  
Kenneth S. Hanus  
William B. Hopf  
Richard H. Hulett

Hermann Koch  
Joseph L. Koepfinger\*  
John Kulick  
David J. Law  
Glenn Parsons  
Ronald C. Peterson  
Tom A. Prevost

Narayanan Ramachandran  
Greg Ratta  
Robby Robson  
Anne-Marie Sahazizian  
Virginia C. Sulzberger  
Malcolm V. Thaden  
Richard L. Townsend  
Howard L. Wolfman

\*Member Emeritus

Also included are the following nonvoting IEEE-SA Standards Board liaisons:

Satish K. Aggarwal, *NRC Representative*  
Richard DeBlasio, *DOE Representative*  
Alan H. Cookson, *NIST Representative*

Michelle D. Turner  
*IEEE Standards Program Manager, Document Development*

Michael D. Kipness  
*IEEE Standards Program Manager, Technical Program Development*

# Contents

1.	Overview.....	1
1.1	Scope.....	2
1.2	Purpose.....	2
1.3	TRC limitations.....	3
2.	Normative references.....	3
3.	Definitions.....	3
4.	Structure of this standard.....	4
4.1	Formats from STIL.0.....	4
4.2	Additional formatting conventions.....	5
4.3	Dependencies on IEEE Std 1450.1.....	5
5.	STIL syntax description.....	6
5.1	Additional reserved words.....	6
5.2	Keywords used in a TRC block.....	6
6.	Statement usage and organization by flow.....	7
6.1	TRC usage for ATE constraint specification.....	8
6.2	TRC usage for design/pattern constraints.....	9
6.3	TRC usage for pattern reporting.....	9
6.4	TRC usage for tester targetting.....	10
7.	STIL statement.....	10
7.1	STIL syntax.....	11
7.2	STIL example.....	11
8.	Variables block extension.....	11
8.1	Variables block syntax.....	11
8.2	Variables example.....	12
9.	Resource statement.....	13
9.1	Resource statement syntax.....	13
10.	TRC: TestResourceConstraints block.....	14
10.1	TRC syntax.....	15
10.2	TRC example.....	18
10.3	TRC block sharing rules.....	19
11.	TRC: SignalAttributes.....	19
11.1	TRC: SignalAttributes—syntax.....	19
11.2	TRC: SignalAttributes—examples.....	21

12.	TRC: DCResourceAttributes .....	22
12.1	TRC: DCResourceAttributes—syntax .....	22
12.2	TRC: DCResourceAttributes—example .....	24
13.	TRC: PeriodAttributes .....	25
13.1	TRC: PeriodAttributes—syntax .....	25
13.2	TRC: PeriodAttributes—examples .....	26
14.	TRC: WaveformAttributes .....	26
14.1	TRC: WaveformAttributes—syntax .....	27
14.2	TRC: WaveformAttributes—examples .....	31
15.	TRC: WaveformDescriptions .....	32
15.1	TRC - WaveformDescriptions—syntax .....	32
15.2	TRC: WaveformDescriptions—examples .....	34
16.	TRC: PatternAttributes .....	35
16.1	TRC: PatternAttributes—syntax .....	35
16.2	TRC: PatternAttributes—examples .....	38
17.	TRC: NameChecks block .....	39
17.1	NameChecks block—syntax .....	39
17.2	NameChecks—examples .....	40
	Annex A (informative) Glossary .....	42
	Annex B (informative) Fluid concepts in parameter specification .....	48
	Annex C (informative) Tester channel model .....	50
	Annex D (informative) Example of TRC for a simple tester model .....	52
	Annex E (informative) Example of TRC used to define waveforms and timing .....	54
	Annex F (informative) Example of TRC used for resource reporting .....	58
	Annex G (informative) Example of tester targeting and tester loading .....	61
	Annex H (informative) Example of vector memory checking .....	66
	Annex I (informative) Waveform generator model .....	69
	Annex J (informative) File encryption .....	75
	Annex K (informative) Regular expression reference .....	76

Currently in preview, click buy full version

# IEEE Standard for Extensions to Standard Test Interface Language (STIL) (IEEE Std 1450<sup>TM</sup>-1999) for Tester Target Specification

## 1. Overview

The STIL environment supports transferring tester-independent test programs to a specific automated testing equipment (ATE) system. Although native STIL data are tester independent, the actual process of mapping the test program onto tester resources may be critical, and it is necessary to be able to completely and unambiguously specify how the STIL programs and patterns are mapped onto the tester resources. TRC (which stands for either tester resource constraints or tester rules checking, depending on the usage) is an extension to the STIL language to facilitate this operation.

Figure 1 shows the usage model for tester targeting. The four ways that the TRC statements come into play in the flow of data from design to test are indicated by the circled numbers in the diagram. These four uses are defined as follows:

- a) **Tester rules checking:** As early as possible in the process of inserting “Design for Test” logic and generation of test patterns, the rules of the target tester are identified by means of the TRC file defining the target tester.
- b) **Tester resource reporting:** As part of the pattern generation process, a report of resources required for the pattern may be created in TRC format. This information is available for test planning purposes, such as 1) when a pattern is for an embedded core to be integrated into a chip or 2) for tester scheduling purposes. Each resource report is associated with a particular STIL file/stream. The resource report data may be a separate file (as implied in the above diagram) or may be included in the STIL pattern file.
- c) **Tester resource targeting:** The process of tester targeting is that of adding additional information into the STIL file/streams that specifies how the resources of a given tester are to be assigned. Note the bars on the left side of the diagram, which indicate that this targeting operation can be done in one of three places: 1) by the EDA software that generates the patterns, 2) by software created by the test user, or 3) by the ATE software that loads the STIL patterns.
- d) **Tester resource loading:** The tester loader is a process that maps the device-oriented STIL data to the resources of the tester. There may or may not be targeting information provided. If targeting information is not present, then the loader is expected to do the job of assigning resources. If targeting information is present, then it is to be used to direct the resource assignment.